EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| L15 | 2 | uejima-kazuya.in. | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 09:45 |
| L16 | 89 | kubo-minoru.in. | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 09:57 |
| L17 | 62 | kubo-minoru.in. and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 09:57 |
| L18 | 6198 | (source "drain") with (plasma "gas") with dop$3 | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 10:29 |
| L19 | 979 | (source "drain") with (plasma "gas") with impurity with dop$3 | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 10:30 |
| L20 | 532 | (source "drain") with (plasma "gas") with impurity with dop$3 and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 10:30 |
| L21 | 79 | (source "drain") with (plasma "gas") with impurity with dop$3 same transistor and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 10:30 |
| L22 | 6 | ("4733284" | "4864376"). PN. OR ("5864149").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 10:31 |
| L23 | 1580 | (source "drain") with low with impurity with gate and @py<"2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 13:15 |
| L24 | 57 | (source "drain") with low with impurity with gate with "near" and @py<"2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 13:16 |
| L25 | 31 | (source with drain) with low with impurity with gate with "near" and @py<"2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 13:25 |

| L26 | 37 | (source with drain) with low with impurity with concentration with "near" and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 13:25 |
|---|---|---|---|---|---|---|
| L27 | 36 | MISFET with strained with channel | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/29 15:08 |
| L28 | 49 | ("4442449" \| "4975387" \| "5218213" \| "5521108" \| "5759898" \| "6059895" \| "6228692").PN. OR ("6607948").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:12 |
| L29 | 115 | 257/288.ccls. and MISFET | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:14 |
| L30 | 618047 | 257/288, "190", "616".ccls. and (MISFET with strained with channel) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:15 |
| L31 | 618047 | 257/288, "190", "616".ccls. and (MISFET with strained with channel with impurity ) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:15 |
| L32 | 618047 | 257/288, "190", "616".ccls. and (MISFET with strained near1 channel with impurity ) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:15 |
| L33 | 618047 | 257/288, "190", "616".ccls. and (MISFET) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:16 |
| L34 | 2866 | 257/288, "616".ccls. and (MISFET) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:16 |
| L35 | 2866 | 257/288, "616".ccls. and (MISFET) and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:16 |
| L36 | 29 | 257/616.ccls. and (MISFET) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:16 |
| L37 | 107 | 257/192.ccls. and (MISFET) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/29 15:19 |
| L38 | 81 | 257/192.ccls. and (MISFET) | USPAT | OR | ON | 2008/10/29 15:20 |
| L39 | 58 | 257/288.ccls. and (MISFET) | USPAT | OR | ON | 2008/10/29 15:21 |
| L40 | 1 | 257/288.ccls. and (MISFET with strained) | USPAT | OR | ON | 2008/10/29 15:21 |
| L41 | 289814 | 257/288, "192", "616".ccls. and (MISFET with strained) | USPAT | OR | ON | 2008/10/29 15:21 |
| L42 | 1964 | 257/288, "616".ccls. and (MISFET with strained) | USPAT | OR | ON | 2008/10/29 15:21 |
| L43 | 4 | "257"/"616".ccls. and (MISFET with strained) | USPAT | OR | ON | 2008/10/29 15:21 |
| L44 | 7 | "257"/"192".ccls. and (MISFET with strained) | USPAT | OR | ON | 2008/10/29 15:22 |

| L45 | 74 | "20040135210" 20030227029* "6633066" "6190975" | USPAT | OR | ON | 2008/10/29 15:42 |
|-----|-----|-----|-----|-----|-----|-----|
| L46 | 3 | ("20040135210" 20030227029* "6633066" "6190975").pn. | US-PGPUB; USPAT | OR | ON | 2008/10/29 15:42 |
| L47 | 4 | ("20040135210" "20030227029" "6633066" "6190975").pn. | US-PGPUB; USPAT | OR | ON | 2008/10/29 15:44 |
| S1 | 2 | (MISFET "MIS field effect transistor") with (base "substrate") with strained with impurity | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:19 |
| S2 | 2 | uejima-kazuya$.in. | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:20 |
| S3 | 843 | impurity with concentration with depth with transistor | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:21 |
| S4 | 7487 | MISFET | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:21 |
| S5 | 269 | MISFET same impurity same depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:22 |
| S6 | 4 | S5 same S4 same S3 | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 13:22 |
| S7 | 13 | ("4007478" \| "4232439" \| "4969020" \| "5254866" \| "5382536" \| "5386136" \| "5441906").PN. OR ("5905284").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:24 |
| S8 | 4357 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:28 |
| S9 | 88 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") with impurity with depth | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:28 |

| S10 | 88 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") with impurity with (depth "Tp") | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:29 |
|---|---|---|---|---|---|---|
| S11 | 42 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") with impurity with (depth "Tp") with concentrat$3 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:29 |
| S12 | 3 | ("6927414" \| "7141477" \| "7172935").PN. OR ("7436046").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:30 |
| S13 | 10 | ("20010041432" \| "20020058385" \| "5171703" \| "6184112" \| "6190179" \| "6333217" \| "6368928" \| "6432802" \| "6696341").PN. OR ("7141477").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:42 |
| S14 | 6 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") with strained with impurity | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:48 |
| S15 | 126 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors")same SiGe | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:49 |
| S16 | 126 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") same SiGe | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:49 |
| S17 | 28 | (MISFET "Metal-Insulator Semiconductor Field Effect Transistors") same SiGe with concentration | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:52 |
| S18 | 10 | ("20020006058" \| "20040041217" \| "20040141367" \| "20050117617" \| "20060043443" \| "5457335" \| "5659499" \| "5874760" \| "6069820" \| "6753562").PN. OR ("7397071").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 13:53 |
| S19 | 1051 | (base "substrate") with (SiGeC) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 14:03 |
| S20 | 1 | (base "substrate") with (SiGeC) with MISFET | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 14:04 |
| S21 | 36 | (base "substrate") with (SiGeC) with strained | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 14:05 |
| S22 | 50 | (base "substrate") with (Si$Ge$C) with strained | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 14:09 |

| S23 | 252 | ("5798293" "5461250" "4829346" "5777364" "5821577" "6004137" "6583015" "6690043" "6774390" "6846715" "7033913" "7166867" "7217668" "7417257" "7436046" "20020068393" "20020104993" "20030207571" "20030227036" "20040126958" "20040227186" "20050139891" "20050173738" "20050202640" "20060073664" "20070082470" "20070090373" "20070108514" "20070235802" "20080179752" "5491348" "5497024" "5780328" "5973364" "6174773" "6650565" "6720596" "6847071" "6859381" "6949780" "20020043676" "20020185690" "20030094640" "20040165430" "20040211994" "6943407" "7205604" "20040157353" "20040256639" "20060292762" "20070148939" "20070241367" "20080105910" "20080237637" "5940723" "6847093" "20040009636" "5446689" "5587722" "5937290" "6509277" "6833331" "6051509" "4568958" "5410173" "5514895" "5661061" "5693964" "4818716" "4904615" "5319221" "5643811" "6001710" "6069038" "6091110" "4549340" "4557036" "4898840" "5202275" "5278089" "5331191" "5354699" "5512497" "5523588" "5557147" "5610856" "5633513" "5714774" "5739589" "5780882" "5804483" "5811316" "6030876" "6127255" "6165825" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:16 |

| | | "6169324" "6201280" "6215144" "6215144" "4258465" "4356041" "4755867" "4782037" "4803534" "4824804" "4872041" "4890148" "4901128" "4954851" "4960718" "4962050" "4987462" "4990461" "4990990" "4990998" "4994868" "5191402" "5208477" "5208782" "5214496" "5219770" "5237528" "5239196" "5276339" "5278136" "5298765" "5300790" "5300795" "5376569" "5382565" "5382809" "5455432" "5539248" "5543652" "5572480" "5604365" "5612564" "5612557" "5652457" "5656836" "5698869" "5701026" "5700704" "5705835" "5723374" "5731219" "5767554" "5828079" "5834851" ).pn. | | | | |
|---|---|---|---|---|---|---|
| S24 | 549 | S3 not (@ad>"20040108" @pd>"20040108") | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:17 |
| S25 | 549 | S3 not (@ad>"20040108" @pd>"20040108") and impurity | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:18 |
| S26 | 549 | S3 not (@ad>"20040108" @pd>"20040108") and impurity and depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:18 |
| S27 | 544 | S24 and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:19 |
| S28 | 195 | S23 and MISFET | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:20 |

| S29 | 152 | S23 and MISFET and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:21 |
|---|---|---|---|---|---|---|
| S30 | 88 | S23 and MISFET and @py<"2004" and impurity | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:21 |
| S31 | 27 | S23 and MISFET and @py<"2004" and (impurity same depth) | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:21 |
| S32 | 30 | ("5107315" \| "5173761" \| "5254862" \| "5298765"). PN. OR ("5382809").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 15:23 |
| S33 | 743295 | (base "substrate" same strained same active same cencentration).clm. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 15:35 |
| S34 | 270 | (base same gate same impurity same concentration).clm. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:36 |
| S35 | 263 | (base same gate same impurity with concentration).clm. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:37 |
| S36 | 134 | (base with gate with impurity with concentration).clm. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:37 |
| S37 | 402 | (base with gate with impurity with concentrationwith source with strained).clm. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:37 |
| S38 | 32 | (base with gate with impurity with concentration with (strained "channel")). clm. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 15:37 |

| S39 | 3 | MISFET with strain$2 with channel with impurity | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 16:58 |
|---|---|---|---|---|---|---|
| S40 | 49 | MISFET with strain$2 with channel | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 16:59 |
| S41 | 10 | MISFET with strain$2 with channel and @py< "2004" | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/10/27 16:59 |
| S42 | 173 | ("4597160" \| "4697197" \| "4841481" \| "4918510" \| "4921813" \| "4992386" \| "5019882" \| "5140391" \| "5272365").PN. OR ("5461250").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/27 16:59 |
| S43 | 11 | Tp with impurity with concentration | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:32 |
| S44 | 5751 | impurity with concentration with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:33 |
| S45 | 48 | impurity with concentration with depth with MIS | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:33 |
| S46 | 26 | impurity with concentration with depth with MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:33 |
| S47 | 836 | impurity with concentration with depth with (source or drain) and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:36 |
| S48 | 14 | MIS same impurity with concentration with depth with (source or drain) and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 08:36 |

| S49 | 13 | ("4908327" \| "4924277" \| "4956311" \| "5036019" \| "5216272" \| "5334870" \| "5413945" \| "5492847" \| "5532176").PN. OR ("5877531").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 08:42 |
|-----|-----|------------------------------------------------------------------------------------------------------------------------------|------------------------|-----|----|------------------|
| S50 | 8 | ("4247861" \| "4484388" \| "5005066").PN. OR ("5838048").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 08:42 |
| S51 | 0 | MIS same amorphrous with layer with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:20 |
| S52 | 0 | MIS same amorphrous with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:21 |
| S53 | 0 | amorphrous with channel with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:21 |
| S54 | 80 | amorphous with channel with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:21 |
| S55 | 21 | impurity with amorphous with channel with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:21 |
| S56 | 2 | amorphous near1 layer with channel with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 11:24 |
| S57 | 1 | amorphous adj1 layer with channel with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:51 |
| S58 | 1474 | amorphous adj1 layer with (depth "thickness") | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:51 |
| S59 | 55 | amorphous adj1 layer with (depth "thickness") with impurity | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:51 |

| S60 | 31 | amorphous adj1 layer with (depth "thickness") with impurity and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:52 |
|---|---|---|---|---|---|---|
| S61 | 0 | amorphous adj1 layer with (depth "thickness") with channel with impurity and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:52 |
| S62 | 9 | amorphous adj1 layer with (depth "thickness") with channel and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:55 |
| S63 | 34 | amorphous adj1 layer with (depth "thickness") with (source or drain) and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:56 |
| S64 | 4 | amorphous adj1 layer with (depth "thickness") with (source or drain) with ion and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:56 |
| S65 | 34 | amorphous adj1 layer with (depth "thickness") with (source or drain) and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:58 |
| S66 | 0 | amorphous adj1 layer with (depth "thickness") with (source or drain) with maximum and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:59 |
| S67 | 6 | amorphous with (depth "thickness") with (source or drain) with maximum and @py<"2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 12:59 |
| S68 | 2 | uejima-kazuya | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 13:08 |
| S69 | 2 | uejima-kazuya.in. | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 13:08 |

| S70 | 2790 | (source "drain") with impurity with depth | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 13:59 |
|-----|------|------|------|-----|-----|------|
| S71 | 282 | (source "drain") with impurity with depth and MIS | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 13:59 |
| S72 | 149 | (source "drain") with impurity with depth and MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 13:59 |
| S73 | 81 | (source "drain") with impurity with depth with concentration and MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 14:00 |
| S74 | 28 | (source "drain") with impurity with depth with concentration with channel and MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 14:00 |
| S75 | 6 | (source "drain") with impurity with depth with concentration with channel same MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 14:00 |
| S76 | 14 | (source "drain") with impurity with depth with channel same MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 14:01 |
| S77 | 24 | (source "drain") with impurity with (depth "thickness") with channel same MIS and @py< "2004" | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 14:02 |
| S78 | 21685 | impurity with implant$3 with region | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 15:47 |
| S79 | 850 | impurity with implant$3 with region with gate with wall | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 15:48 |

| S80 | 7 | impurity with implant$3 with region with gate with wall with MIS | US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB | OR | ON | 2008/10/28 15:48 |
|-----|-----|------|------|------|------|------|
| S81 | 36 | ("4442589" \| "4455738" \| "4478679").PN. OR ("4597827").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 15:50 |
| S82 | 24 | ("4312680" \| "4419809" \| "4559693" \| "4597827" \| "4729966" \| "4769339" \| "5001077").PN. OR ("5112766").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 15:54 |
| S83 | 18 | ("4312680" \| "4419809" \| "4597827" \| "4994904" \| "5091763" \| "5108939" \| "5256586" \| "5286664" \| "5541132" \| "5661048"). PN. OR ("5879999").URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 15:55 |
| S84 | 841 | impurity with implant$3 with region with thickness | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:03 |
| S85 | 389 | impurity with implant$3 with region with thickness with gate | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:03 |
| S86 | 1 | impurity with implant$3 with region with thickness with gate with MIS | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:03 |
| S87 | 212 | impurity with implant$3 with region with thickness with gate and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:03 |
| S88 | 1488 | impurity with implant$3 with region with thickness (depth) with (greater) with gate and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:04 |
| S89 | 1709 | impurity with implant$3 with region with thickness (depth) with (greater "larger") with gate and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:04 |
| S90 | 883 | MIS same impurity with implant$3 with region with thickness (depth) with (greater "larger") with gate and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:05 |
| S91 | 881 | MIS same wall with impurity with implant$3 with region with thickness (depth) with (greater "larger") with gate and @py< "2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:06 |

| S92 | 881 | MIS same strained with impurity with implant$3 with region with thickness (depth) with (greater "larger") with gate and @py<"2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:07 |
| S93 | 7 | MIS same (strained with impurity with implant$3 with region with thickness (depth) with (greater "larger") with gate) and @py<"2004" | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:07 |
| S94 | 1 | MISFET with abnormal with leakage with current | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:29 |
| S95 | 2475535 | MISFET with abnormal with I current | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:29 |
| S96 | 6 | MISFET with abnormal with current | US-PGPUB; USPAT; USOCR | OR | ON | 2008/10/28 16:30 |

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